



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Inventor	Joonhyung Kwon	Filing Date	December 29, 2003
Art Unit	2856	Examiner	LARKIN, Daniel Sean
Title:	Scanning Probe Microscope With Improved Probe Tip Mount		
Docket No.:	PSI004-1C US	Application No.	10/748,827

Santa Clara, California
February 1, 2005

Mail Stop AMENDMENT
COMMISSIONER FOR PATENTS
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT

Dear Sir:

This amendment is in response to the Office Action dated November 1, 2004.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 3 of this paper.

Amendments to the Drawings begin on page 8 of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

Remarks/Arguments begin on page 9 of this paper.

An **Appendix** of one sheet which includes amended drawing figures is attached, following page 13 of this paper.

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